

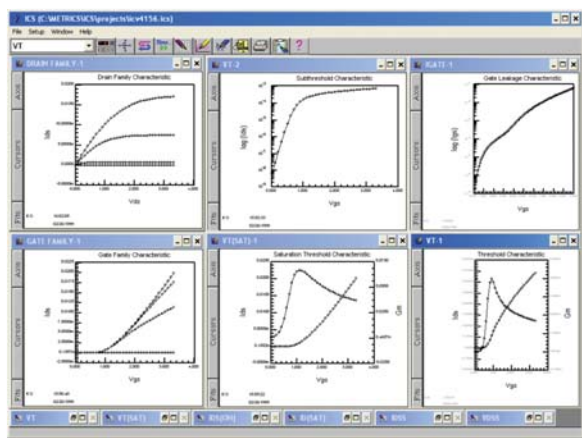
ICS (Interactive Characterization Software)

Point. Click. Measure. It's as simple as that.

Metrics™ ICS controls specialized semiconductor test and measurement instrumentation. It provides easy setup for complex instrumentation through an interactive graphical user interface, and requires no programming by the end user. It has a full suite of data analysis tools and provides quick transfer of data to popular software packages such as spreadsheets, word processors, and databases. This popular software product is a productive application for performing interactive characterization measurements on semiconductor devices.

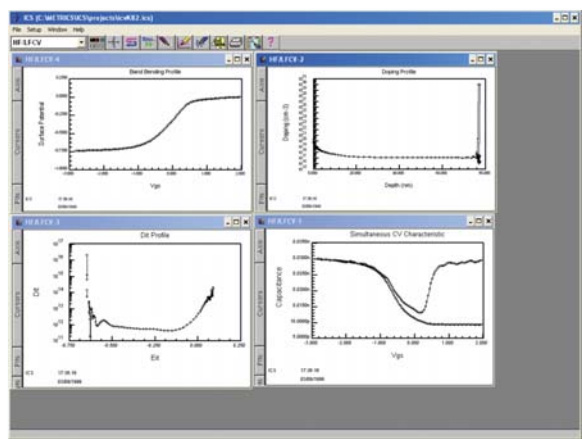
POINT, CLICK, AND MEASURE CAPABILITIES

- Controls instrumentation from multiple manufacturers with a single, easy-to-use graphical interface environment.
 - Semiconductor parameter analyzers
 - CV/LCRZ meters
 - VBScript integration for end user driver development
- Provides programming-free test setup generation.
- Supports multiple measurement mainframe modes.
- Supports multiple instrument support.



GRAPHIC AND DATA ANALYSIS

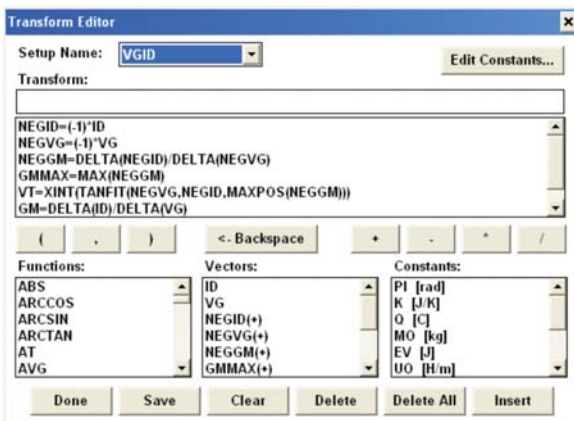
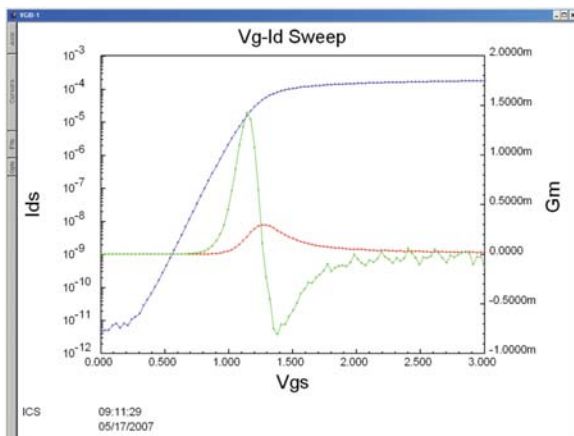
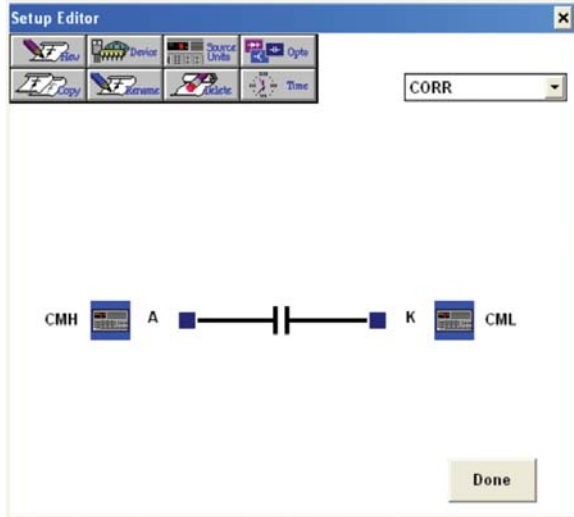
- Delivers spreadsheet functionality.
- Provides powerful plotting capabilities.
- Dynamically links data to other spreadsheet programs and databases.
- Uses Windows clipboard flexibility to incorporate plots into documents and presentations.



COMPREHENSIVE DATA MANAGEMENT

- Uses project files as a central location to store test setups and data.
- Includes ASCII export of data, which allows for advanced analysis on workstation, Mac, and PC-based engineering tools.
- Delivers advanced post-measurement search and report capabilities.

Configure measurement routines without writing a single line of code



PARAMETRIC EXTRACTION WITH ICS

Use the ICS plot window to interactively extract parameters using cursors, line-fitting tools, and axis control. The plot line coloring makes visualizing the data easier.

GRAPHICAL TEST GENERATION

Use the graphical setup editor to configure measurement routines without writing a single line of code. Instrument and test fixture connections are created by matching instrument icons to the terminals of a workspace schematic device under test (DUT). A single click at each module or channel icon opens a setup dialog that is unique to each source of the instrument.

ICS APPLICATIONS

Device Characterization

Automatically characterize new devices using auto-sequence execution of measurements. Data is stored based on user-defined attributes such as process, lot, wafer, die, and more.

Process Monitoring

Solve in-line production problems by tracking parameters such as line width, resistivity, and mask alignment. Automatically export results to generate early warning reports.

Failure Analysis

Debug VLSI subcircuits by using ICS's suite of measurement modes and powerful analysis functions to efficiently assess failures. SMUs in standby mode remain programmed as other SMUs are reset for the next measurement, eliminating the need for external power supplies.

Incoming Inspection

Automate your inspection of large quantities of devices by dynamically linking measured or extracted data, and performing comparisons to upper and lower control limits.

Process Development

Automate parameter extraction such as threshold voltage using the numerical transform editor. The transform editor defines nested equations used to extract parameters from measured data.